



Laboratoire LEPRINCE-RINGUET

École polytechnique - IN2P3/CNRS

LLR



CENTRE NATIONAL
DE LA RECHERCHE
SCIENTIFIQUE

IN2P3

INSTITUT NATIONAL DE PHYSIQUE NUCLÉAIRE
ET DE PHYSIQUE DES PARTICULES

From today design ... to

Final and realistic design

Why a difference

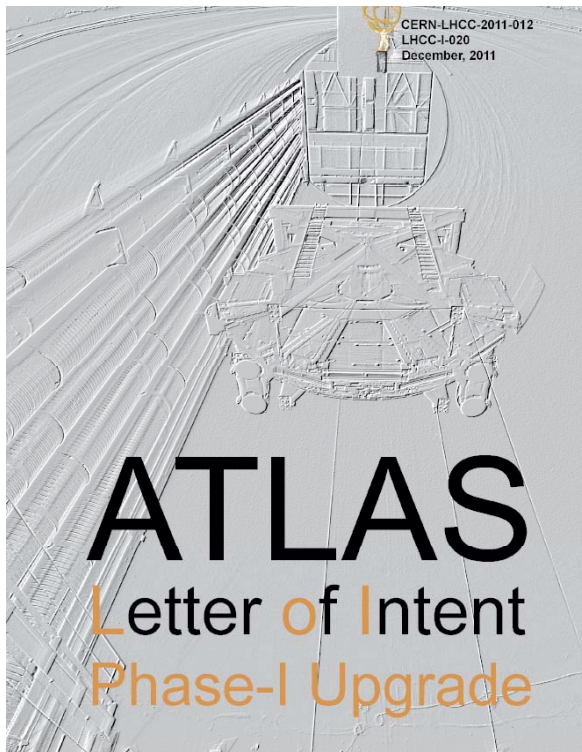
- ① lessons from last 3 years that some technical challenges are just dreams of physicists and just not realistic for engineers/producers....

- ② The cost estimation looks more than ever unfavourable (choose cheaper techno.)

- ③ read again “The 10 Commandments” for a real detector
 - minimise the number of technology
 - minimise the risk (moderate number of innovative technology)
 - minimise the difficulty of assembling (simpler is better)
 - OF COURSE, COST in part of the choiceEtc....
and last but not least, a full detector is not a prototype in larger size !!!!

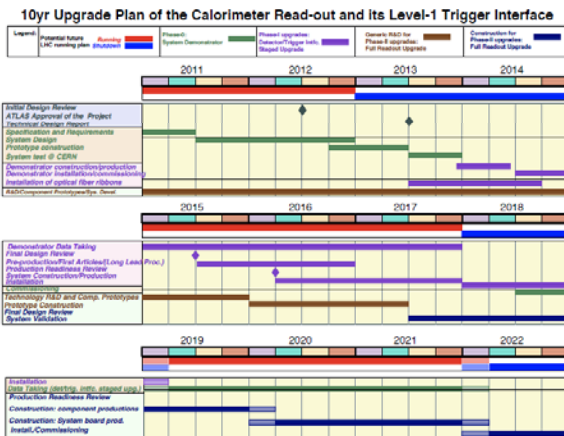
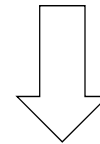
- ④ Remember that the manpower will not be there , when compare to previous detector construction (Upgrade LHC detectors and HEP physics in the poor parents now)
..... production and construction more comparable to space science

see next slide



Funding , manpower in the next 8 years

- > financial crisis
- > LHC upgrade
- > HEP versus applied science → Impact on manpower resource !!!!



Today manpower resource on ECAL is very modest

In any case, much smaller than the 1st prototype time
While this proto. was based on classic technologies

“Chercher l’erreur”

For a “known” technology, it took 5 years to establish the feasibility and readiness of the mechanics of one “barrel” module of ECAL



we can't really be ready in 3-4 years with **VERY INNOVATIVE** solutions , where many years of R&D for feasibility study are needed

Readout system

Since we have not 10 years of R&D and
Since there is not 50 people working on the subject....

⇒ forget the DC coupling

By far, too much sensitive to noise and ground loops and leaks and ...

⇒ forget the autotrigger (or constraint it by external clock/trigger)

it is too much dependant on the level of noise in the detector !!
(device behavior, environment condition, ...)

The system must be able to survive whatever the condition

⇒ VFE optimise running at ILC, but possibility to test in TB

(external trigger and memory pile adapted i.e. 6 events in pile is by far too short)

⇒ A **SPECIAL VFE chip** , with lower dynamics (up to 5 mip), to be used to validate and calibrate the wafers in TB (special case)

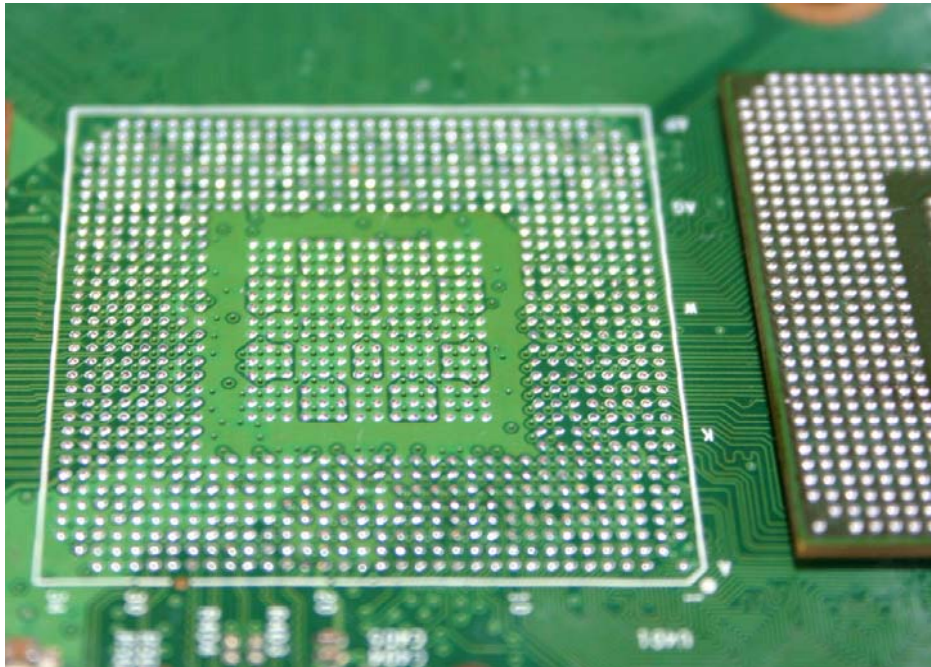
(better precision in smaller time of TB due to smaller noise)

VFE CHIP

Due to silicon wafer cost, it is MANDATORY to burn out the chip before use !!!

→ VFE MUST be packaged in thin but cheap techno.
(possible 1 mm thick ?) → ADAPT chip design to this requirements

→ connection Bump bonded, ?? Different geometry (not a square)
(1 ADC/ch. (or faster ADC for > 1 ch.) ??



Amkor Technology

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Home > Packaging > All Packages > FCMBGA (Flip Chip Molded Ball Grid Array)

Packaging

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Amkor ChipArray[®] BGA 572 LQD 27 x 27 mm

Amkor fcbga

FCMBGA (Flip Chip Molded Ball Grid Array)

Amkor's Flip Chip Molded BGA (FCMBGA) is the evolution of the Super Flip Chip ([SuperFC](#) / FCBGA) high performance flip chip solution. Capillary underfill (CUF) is replaced by molded underfill (MUF). FCMBGA provides additional benefits such as improved board real estate use, by allowing closer spacing between passives and the [flip chip](#) die, better warpage control for thin core [substrates](#) and improved solder joint reliability for passives. FCMBGA also extends the die size range for bare die packages and it is a potential cost reduction over lidded Flip Chip BGA (FCBGA). Advanced molding techniques coupled with next generation mold compounds are used to produce FCMBGA.

FCMBGA packages are designed to allow die protrusion over the mold cap. This ensures the thinnest bond line and best thermal impedance between Flip Chip (FC) die and the attached heat sink.

Flip Chip Molded BGA is produced in an exposed die configuration. This configuration maintains the excellent thermal performance of bare die Flip Chip BGA and it enhances it by providing a support surface around the die for direct heat sink attach. For small to medium die sizes, 8-14mm, H-CMBGA provides excellent coplanarity without the need for a stiffener / lid or formed lid configurations. For larger die sizes, lower CTE substrates coupled with improved molding compound properties are being evaluated.

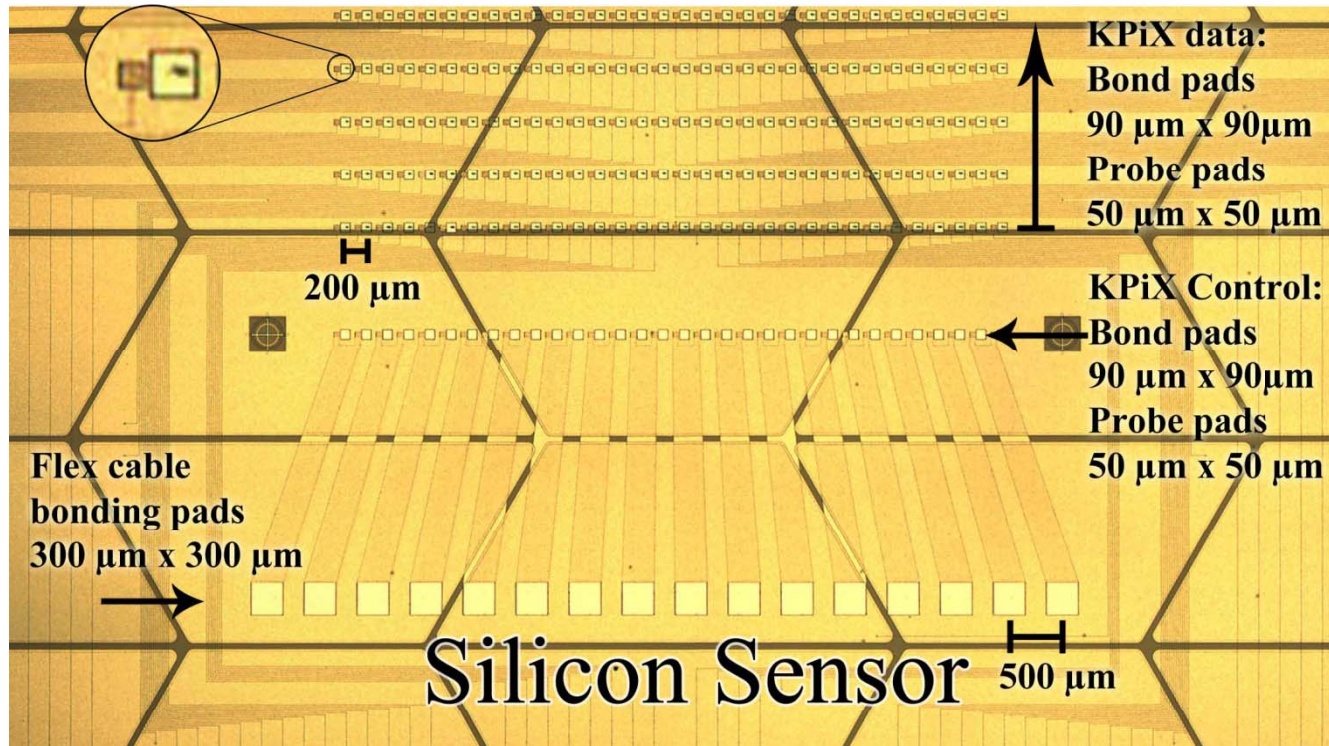
Note: Portfolio based on theoretical calculations - designs not complete for all options. All data on this data sheet is Preliminary.

For more information on the FCMBGA or Flip Chip BGA (FCBGA) packages, please contact an [Amkor Regional Sales Office](#) near you or fill out the [Request Form](#).

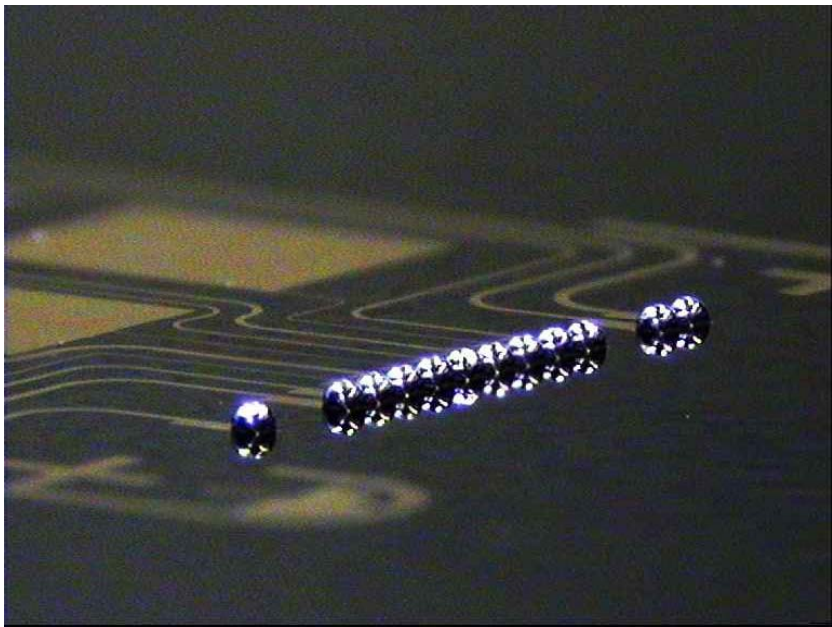
Applications | Features | Reliability | Cross Section | Additional Information | Downloads

As IC fabrication nodes continue to decrease in size, fabrication layers become more fragile. Traditional CUF packages are reaching reliability limits. FCMBGA allows the use of MUF materials where historically CUF materials were required. MUFs are higher filler content and lower moisture absorption than CUFs. Coupled with finer filter particles these materials will allow FCMBGA packaging for ultra low k nodes.

The flexibility of this new IC packaging technology makes it applicable to a wide array of devices including ASIC / FPGA, GPU and CPU's. FCMBGA provides the package solution for networking and storage, gaming, broadband communications, computer, multimedia markets, etc.



SiD ECAL



For cost optimisation, bump bonding, directly on silicon wafer is not recommended

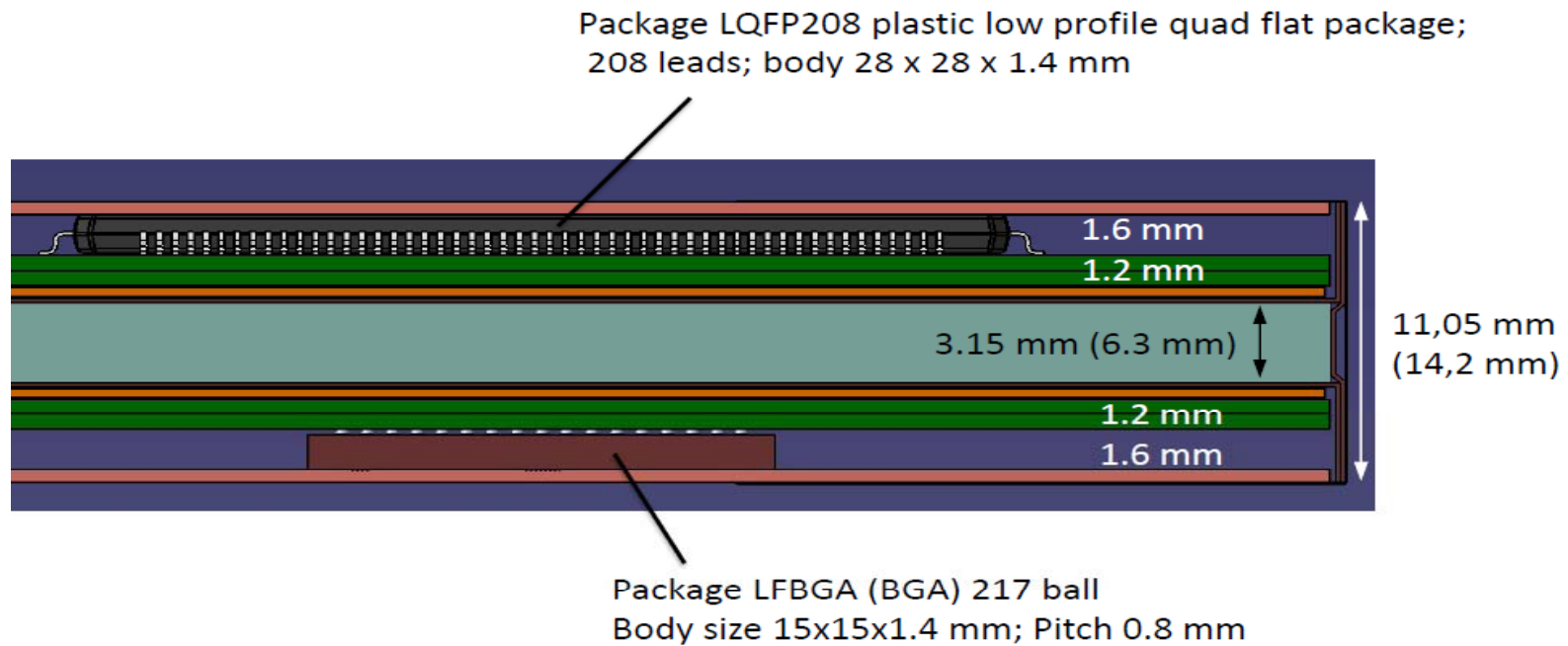
But , why not on PCB !!
(if it is a standard industrial process)

PCB

It is MANDATORY to use “STANDARD” producers in “Classical” techno

→ thickness 0.8 mm in our dream
1.2 mm today (with difficulty)

1.5 or more for final design ?



20 layers

The uncertainty on the silicon cost, lead to the possibility that 15-20 layers could be the maximum number of layers affordable by HEP community....

- ➔ It reduce the cost by the silicon surface, but not only
i.e. the tungsten is cheaper when thicker

For the DBD, the assembling scheme must be given !!!!

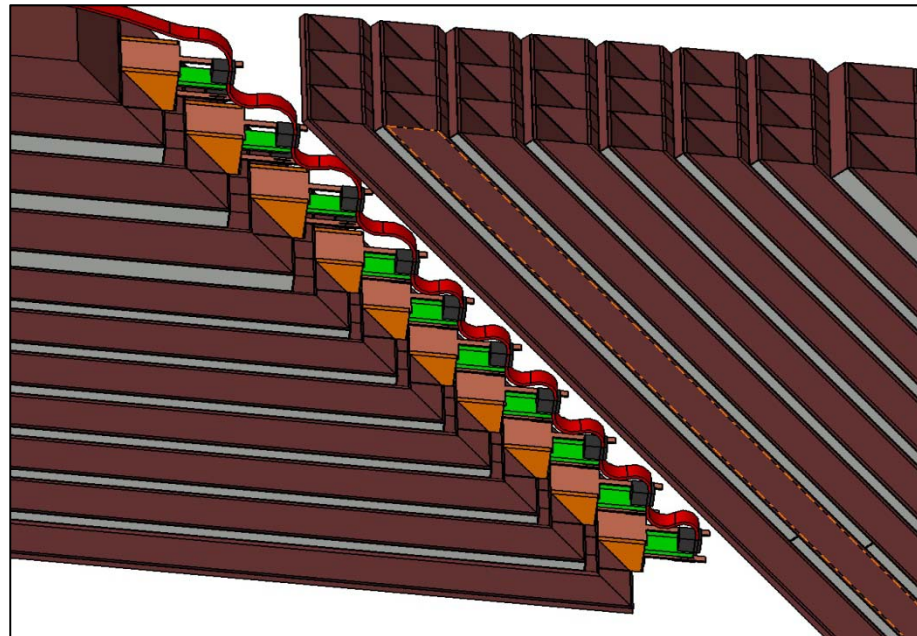
The assembling time, the organisation, the manpower in m/y, etc...

Exemple :

a simple flex kapton running all along the alveoli is better than DIF board

i.e. any electronic (DIF) in the 4 cm gap is challenging, costing and it is not simple to unplug

- ➔ Displace the concentrator on the back of the module (larger surface available)



Design & picture:
Marc Anduze

CONCLUSION

It is time to go down

& go back to

Technically and costly realistic choices

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What is true for si- w ecal